

N t i c o f R e f e r e n c e s C i t e d

Application/Control No.

09/892,878

Applicant(s)/Patent Under
Reexamination
KIM ET AL.

Examiner

Steven H. Rao

Art Unit

2814

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5173542	12-1992	Lau et al.	525/531
	B	US-5328807	07-1994	Tananka et al.	430/311
	C	US-5487811	01-1996	Iizuka	156/656.1
	D	US-5753418	05-1998	Tsai et al.	430/313
	E	US-6071824	06-2000	Singh et al.	438/717
	F	US-6080529	06-2000	Ye et al.	438/318
	G	US-6090674	07-2000	Hsieh et al.	438/301
	H	US-6110837	08-2000	Linliu et al.	438/723
	I	US-6143476	11-2000	Ye et al.	438/318
	J	US-6187687	02-2001	Plat et al.	438/724
	K	US-6187689	02-2001	Tabara	438/738
	L	US-6316166	11-2001	Chi et al.	430/313
	M	US-6331380	12-2001	Ye et al.	430/318

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	Kr-2001019774	03-2001	Korea	Choi	English Abstract.2
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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